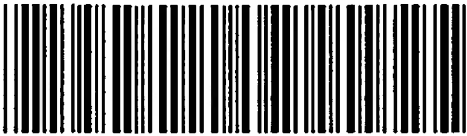


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/052,147	YING ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Huyen X. Vo	2655	

SEARCHED			
Class	Subclass	Date	Examiner
704	9; 10; 232	2/28/2006	HV

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Update EAST search included	2/28/2006	HV